



Preliminary

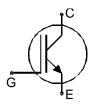
SIGC109T120R3

IGBT³ Chip

FEATURES:

- 1200V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- power module
- Applications:
- drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code
SIGC109T120R3	1200V	100A	10.47 x 10.44 mm ²	sawn on foil	Q67050- A4108-A001

MECHANICAL PARAMETER:

Raster size	10.47 x 10.44 m				
Emitter pad size	8x(2.114 x 4.391)				
Gate pad size	1.139 x 1.139				
Area total / active	109.3 / 85.8	mm ²			
Thickness	140	μm			
Wafer size	150	mm			
Flat position	90	grd			
Max.possible chips per wafer	124 pcs				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	Al, <500µm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



SIGC109T120R3

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit	
Collector-emitter voltage	V _{CE}	1200	V	
DC collector current, limited by T _{jmax}	I _C	100	А	
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	200	А	
Gate emitter voltage	V _{GE}	±20	V	
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C	

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C = 4mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =100A	1.4	1.7	2.1	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C=4mA$, $V_{GE}=V_{CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V_{CE} =1200V , V_{GE} =0V			650	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =30V			600	nA
Integrated gate resistor	R _{Gint}			7.5		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Input capacitance	Ciss	V _{CE} =25V,		7210		pF
Output capacitance	Coss	$V_{GE}=0V$,		377		
Reverse transfer capacitance	Crss	<i>f</i> =1MHz		327		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load

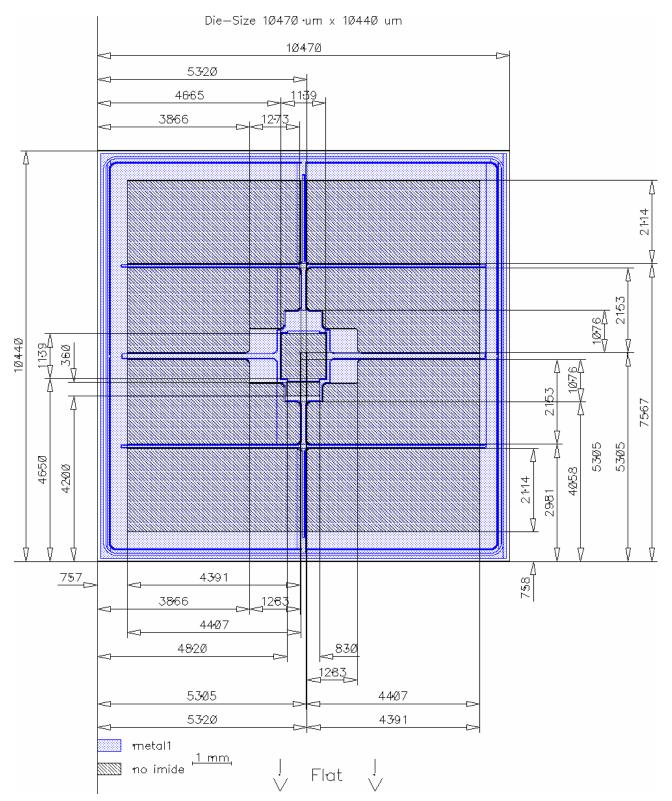
Parameter	Symbol	Conditions	Value			Unit
	Symbol	Conditions	min.	typ.	max.	Unit
Turn-on delay time	t _{d(on)}	<i>T</i> _j =125°C		285		ns
Rise time	t _r	$V_{\rm CC} = 600 \text{V},$		45		
Turn-off delay time	$t_{d(off)}$	· I _C =100A, V _{GE} =-15/15V,		520		
Fall time	t _f	R _G = 3.9Ω		90		

Edited by INFINEON Technologies AI PS DD HV3, L7681A, Edition 2, 26.06.2003



SIGC109T120R3

CHIP DRAWING:





SIGC109T120R3

FURTHER ELECTRICAL CHARACTERISTICS:

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG, Bereich Kommunikation St.-Martin-Strasse 53, D-81541 München © Infineon Technologies AG 2002 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.